

TC74HC4094AP, TC74HC4094AF, TC74HC4094AFN

8-BIT SHIFT AND STORE REGISTER (3-STATE)

The TC74HC4094A is a high speed CMOS 8-BIT SHIFT AND STROBE REGISTER fabricated with silicon gate C²MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

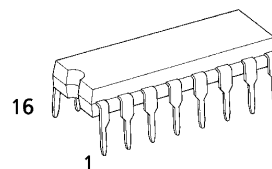
It consists of an 8-bit shift register and an 8-bit latch with 3-state output buffers. Data is shifted serially through the shift register on the positive going transition of the CK input. The output of the last stage (Qs) can be used to cascade several devices. Data on the Qs output is transferred to a second output (Q's) on the following negative transition of the CK input. The data in each stage of the shift register is provided to a corresponding latch, on the negative going transition of the STROBE input. When STROBE is held high, data propagates through the latch to a 3-state output buffer. This buffer is enabled when OUTPUT ENABLE input is set high.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

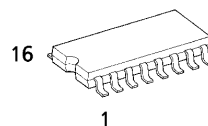
FEATURES:

- High Speed..... $f_{MAX} = 73\text{MHz}(\text{typ.})$ at $V_{CC} = 5\text{V}$
- Low Power Dissipation..... $I_{CC} = 4\mu\text{A}(\text{Max.})$ at $T_a = 25^\circ\text{C}$
- High Noise Immunity..... $V_{NIH} = V_{NIL} = 28\% V_{CC} (\text{Min.})$
- Output Drive Capability 10 LSTTL Loads
- Symmetrical Output Impedance... $|I_{OH}| = I_{OL} = 4\text{mA}(\text{Min.})$
- Balanced Propagation Delays..... $t_{PLH} \approx t_{PHL}$
- Wide Operating Voltage Range.... $V_{CC} (\text{opr.}) = 2\text{V} \sim 6\text{V}$
- Pin and Function Compatible with 4094B

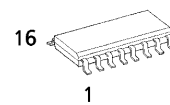
(Note) The JEDEC SOP (FN) is not available in Japan.



P (DIP16-P-300-2.54A)
Weight : 1.00g (Typ.)

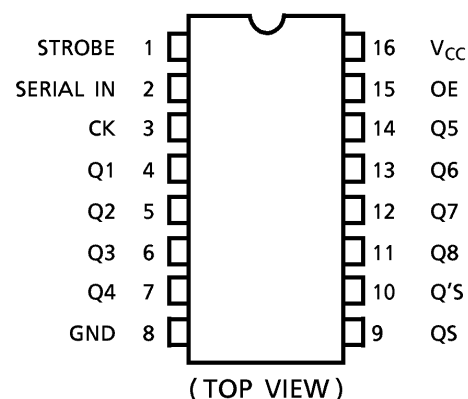


F (SOP16-P-300-1.27)
Weight : 0.18g (Typ.)

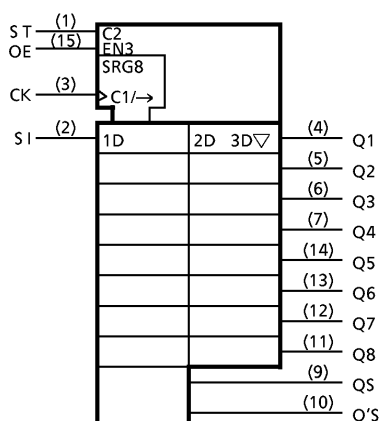


FN (SOL16-P-150-1.27)
Weight : 0.13g (Typ.)

PIN ASSIGNMENT



IEC LOGIC SYMBOL

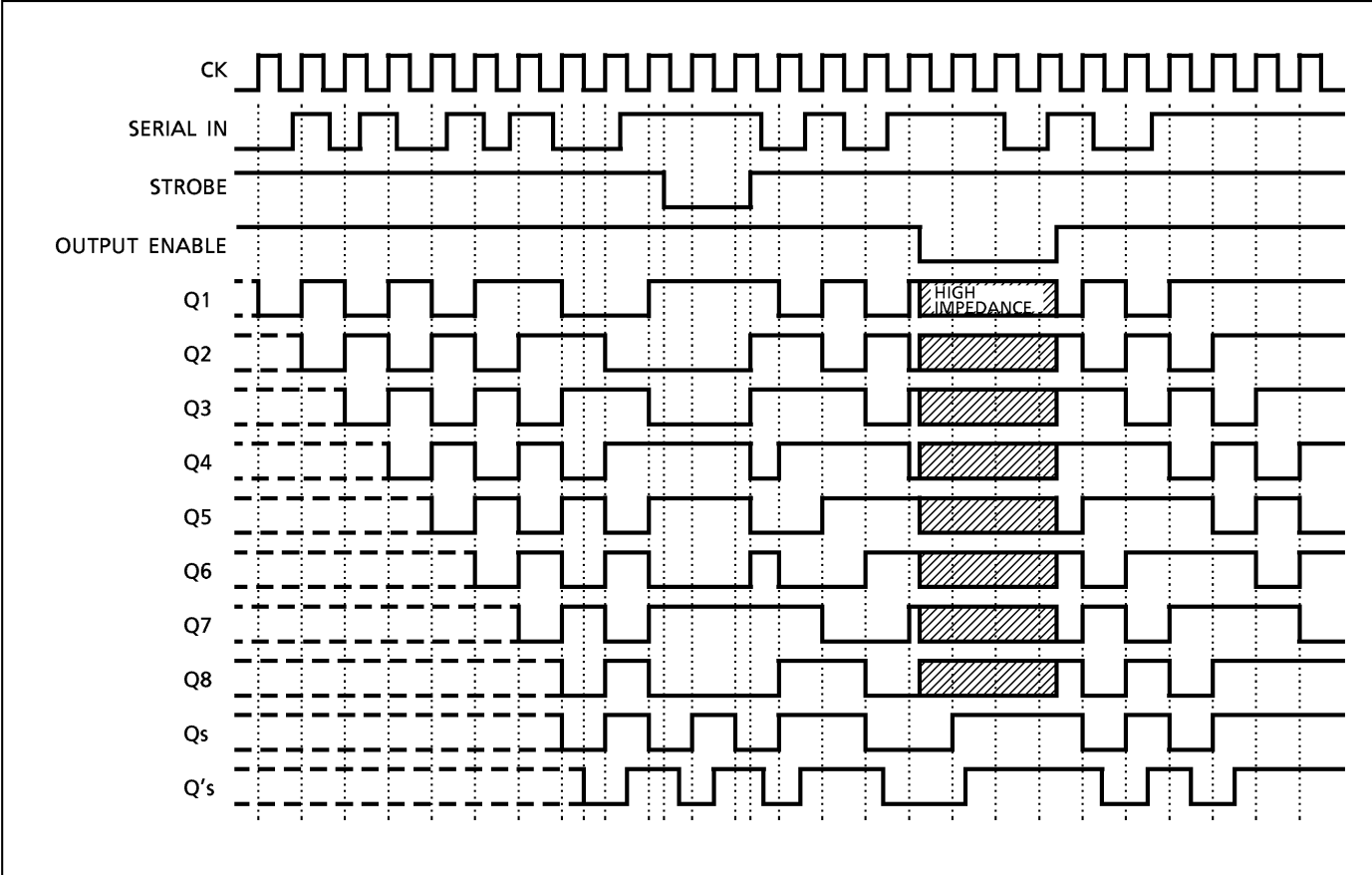


TRUTH TABLE

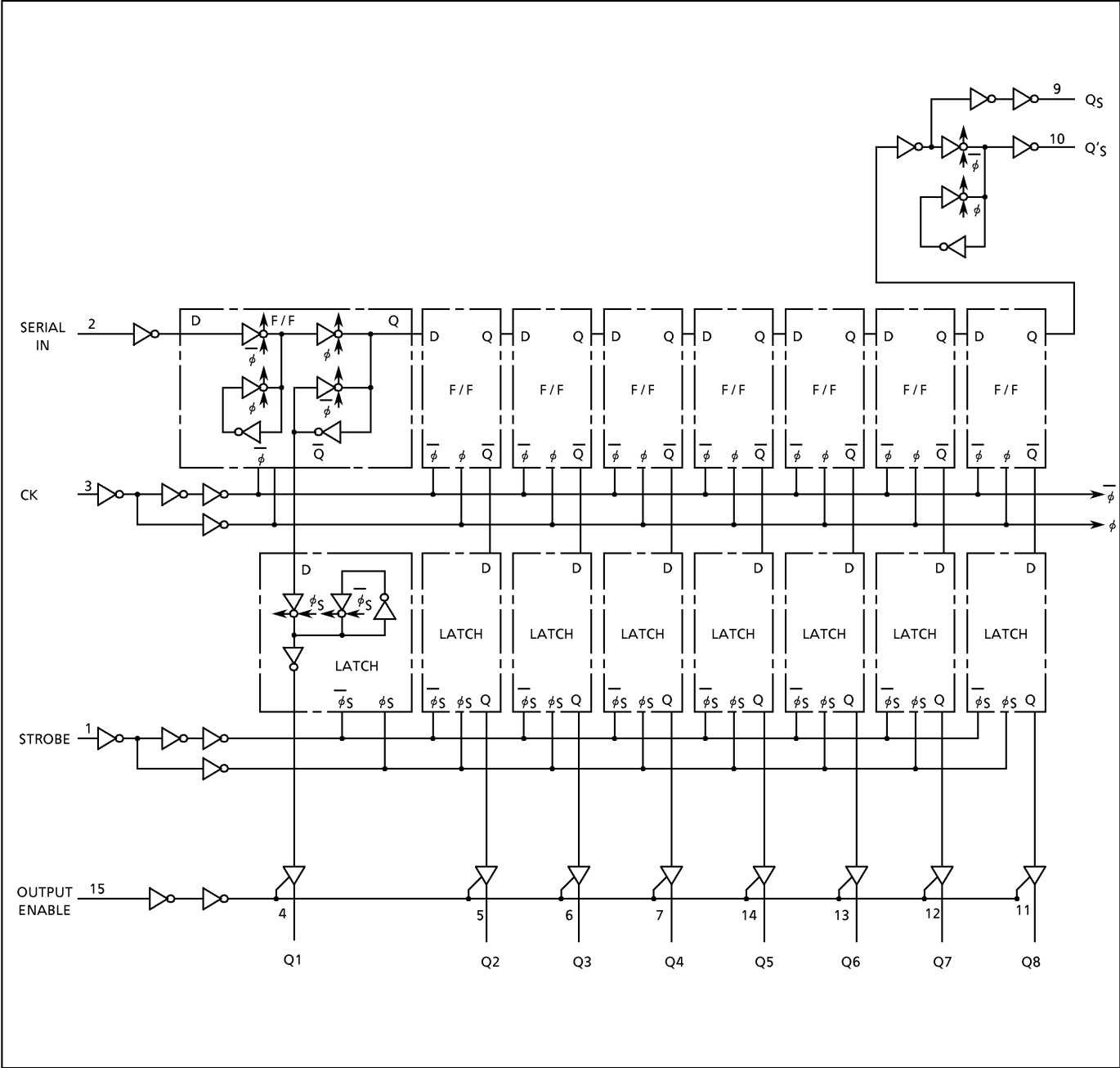
CK	OE	ST	SI	PARA. OUT		SERI. OUT	
				Q1	Qn	Qs	Q's
	H	H	L	L	Qn - 1	Q7	NC
	H	H	H	H	Qn - 1	Q7	NC
	H	L	*	NC	NC	Q7	NC
	L	*	*	Z	Z	Q7	NC
	H	*	*	NC	NC	NC	Qs
	L	*	*	Z	Z	NC	Qs

X : DON'T CARE
NC : NO CHANGE
Z : HIGH IMPEDANCE

TIMING CHART



SYSTEM DIAGRAM



ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	V_{CC}	$-0.5 \sim 7$	V
DC Input Voltage	V_{IN}	$-0.5 \sim V_{CC} + 0.5$	V
DC Output Voltage	V_{OUT}	$-0.5 \sim V_{CC} + 0.5$	V
Input Diode Current	I_{IK}	± 20	mA
Output Diode Current	I_{OK}	± 20	mA
DC Output Current	I_{OUT}	± 25	mA
DC V_{CC} /Ground Current	I_{CC}	± 50	mA
Power Dissipation	P_D	500 (DIP)* / 180 (SOP)	mW
Storage Temperature	T_{stg}	$-65 \sim 150$	$^{\circ}\text{C}$

*500mW in the range of $T_a = -40^{\circ}\text{C} \sim 65^{\circ}\text{C}$. From $T_a = 65^{\circ}\text{C}$ to 85°C a derating factor of $-10\text{mW}/^{\circ}\text{C}$ shall be applied until 300mW.

RECOMMENDED OPERATING CONDITIONS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	V_{CC}	$2 \sim 6$	V
Input Voltage	V_{IN}	$0 \sim V_{CC}$	V
Output Voltage	V_{OUT}	$0 \sim V_{CC}$	V
Operating Temperature	T_{opr}	$-40 \sim 85$	$^{\circ}\text{C}$
Input Rise and Fall Time	t_r, t_f	$0 \sim 1000 (V_{CC} = 2.0\text{V})$ $0 \sim 500 (V_{CC} = 4.5\text{V})$ $0 \sim 400 (V_{CC} = 6.0\text{V})$	ns

DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	V_{CC} (V)	$T_a = 25^{\circ}\text{C}$			$T_a = -40 \sim 85^{\circ}\text{C}$		UNIT
				MIN.	TYP.	MAX.	MIN.	MAX.	
High - Level Input Voltage	V_{IH}		2.0 4.5 6.0	1.50 3.15 4.20	— — —	— — —	1.50 3.15 4.20	— — —	V
Low - Level Input Voltage	V_{IL}		2.0 4.5 6.0	— — —	— — —	0.50 1.35 1.80	— — —	0.50 1.35 1.80	V
High - Level Output Voltage	V_{OH}	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OH} = -20\mu\text{A}$	2.0 4.5 6.0	1.9 4.4 5.9	2.0 4.5 6.0	— — —	1.9 4.4 5.9	— — —	V
			4.5 6.0	4.18 5.68	4.31 5.80	— —	4.13 5.63	— —	
Low - Level Output Voltage	V_{OL}	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OL} = 20\mu\text{A}$	2.0 4.5 6.0	— — —	0.0 0.0 0.0	0.1 0.1 0.1	— — —	0.1 0.1 0.1	V
			4.5 6.0	— —	0.17 0.18	0.26 0.26	— —	0.33 0.33	
3 - State Output Off - State Current	I_{OZ}	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$	6.0	—	—	± 0.5	—	± 5.0	μA
Input Leakage Current	I_{IN}	$V_{IN} = V_{CC} \text{ or GND}$	6.0	—	—	± 0.1	—	± 1.0	
Quiescent Supply Current	I_{CC}	$V_{IN} = V_{CC} \text{ or GND}$	6.0	—	—	4.0	—	40.0	

TIMING REQUIREMENTS (Input $t_r = t_f = 6\text{ns}$)

PARAMETER	SYMBOL	TEST CONDITION	V_{CC} (V)	$T_a = 25^\circ\text{C}$		$T_a = -40 \sim 85^\circ\text{C}$	UNIT
				TYP.	LIMIT	LIMIT	
Minimum Pulse Width (CK)	$t_{W(H)}$ $t_{W(L)}$		2.0	—	75	95	ns
			4.5	—	15	19	
			6.0	—	13	16	
Minimum Pulse Width (STROBE)	$t_{W(H)}$		2.0	—	75	95	
			4.5	—	15	19	
			6.0	—	13	16	
Minimum Set-up Time (SERIAL)	t_s		2.0	—	75	95	
			4.5	—	15	19	
			6.0	—	13	16	
Minimum Set-up Time (STROBE)	t_s		2.0	—	100	125	
			4.5	—	20	25	
			6.0	—	17	21	
Minimum Hold Time (SERIAL)	t_h		2.0	—	0	0	
			4.5	—	0	0	
			6.0	—	0	0	
Minimum Hold Time (STROBE)	t_h		2.0	—	0	0	
			4.5	—	0	0	
			6.0	—	0	0	
Clock Frequency	f		2.0	—	6	5	MHz
			4.5	—	30	24	
			6.0	—	35	28	

AC ELECTRICAL CHARACTERISTICS ($C_L = 15\text{pF}$, $V_{CC} = 5\text{V}$, $T_a = 25^\circ\text{C}$, Input $t_r = t_f = 6\text{ns}$)

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Output Transition Time	t_{TLH} t_{THL}		—	4	8	ns
Propagation Delay Time (CK—Qn)	t_{pLH} t_{pHL}		—	22	35	
Propagation Delay Time (CK—QS, Q'S)	t_{pLH} t_{pHL}		—	16	25	
Propagation Delay Time (STROBE—Qn)	t_{pLH} t_{pHL}		—	16	27	
3-State Output Enable Time	t_{pZL} t_{pZH}	$R_L = 1\text{K}\Omega$	—	13	25	
Maximum Clock Frequency	f_{MAX}		33	73	—	MHz

AC ELECTRICAL CHARACTERISTICS ($C_L = 50\text{pF}$, Input $t_r = t_f = 6\text{ns}$)

PARAMETER	SYMBOL	TEST CONDITION	Ta = 25°C				Ta = -40~85°C		UNIT
			V _{CC} (V)	MIN.	TYP.	MAX.	MIN.	MAX.	
Output Transition Time	t _{TLH} t _{THL}		2.0	—	30	75	—	95	ns
			4.5	—	8	15	—	19	
			6.0	—	7	13	—	16	
Propagation Delay Time (CK—Qn)	t _{PLH} t _{PHL}		2.0	—	92	200	—	250	
			4.5	—	26	40	—	50	
			6.0	—	20	34	—	43	
Propagation Delay Time (CK—QS, Q'S)	t _{PLH} t _{PHL}		2.0	—	65	150	—	190	
			4.5	—	19	30	—	38	
			6.0	—	15	26	—	32	
Propagation Delay Time (STROBE—Qn)	t _{PLH} t _{PHL}		2.0	—	75	160	—	200	
			4.5	—	20	32	—	40	
			6.0	—	16	27	—	34	
3-State Output Enable Time	t _{pZL} t _{pZH}	R _L = 1KΩ	2.0	—	58	150	—	190	
			4.5	—	16	30	—	38	
			6.0	—	13	26	—	32	
3-State Output Disable Time	t _{pLZ} t _{pHZ}	R _L = 1KΩ	2.0	—	35	150	—	190	
			4.5	—	16	30	—	38	
			6.0	—	13	26	—	32	
Maximum Clock Frequency	f _{MAX}		2.0	6	16	—	5	—	MHz
			4.5	30	66	—	24	—	
			6.0	35	80	—	28	—	
Input Capacitance	C _{IN}			—	5	10	—	10	pF
Bus Input Capacitance	C _{OUT}			—	10	—	—	—	
Power Dissipation Capacitance	C _{PD} (1)			—	140	—	—	—	

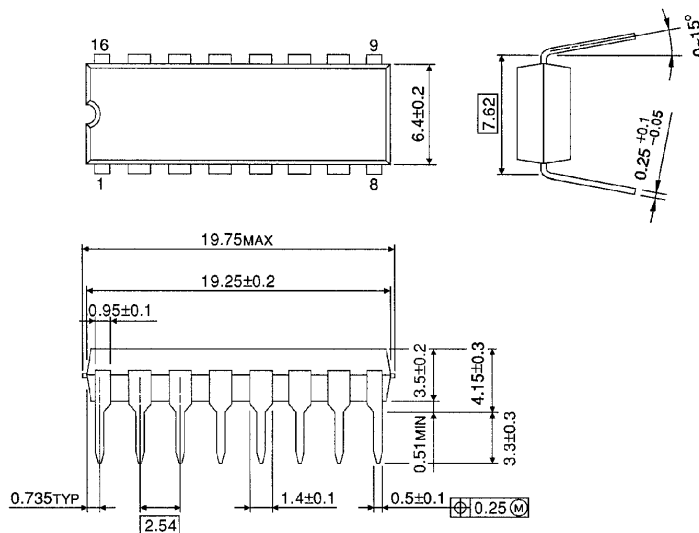
Note (1) C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation :

$$I_{CC}(\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

DIP 16PIN PACKAGE DIMENSIONS (DIP16-P-300-2.54A)

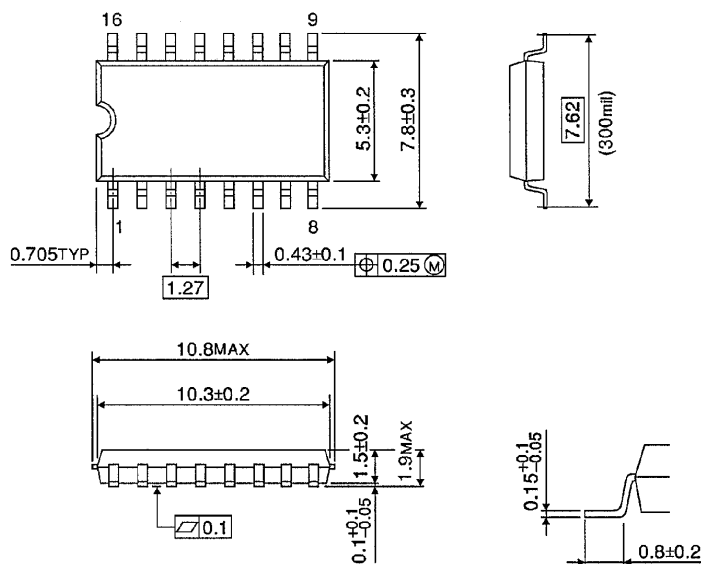
Unit in mm



Weight : 1.00g (Typ.)

SOP 16PIN (200mil BODY) PACKAGE DIMENSIONS (SOP16-P-300-1.27)

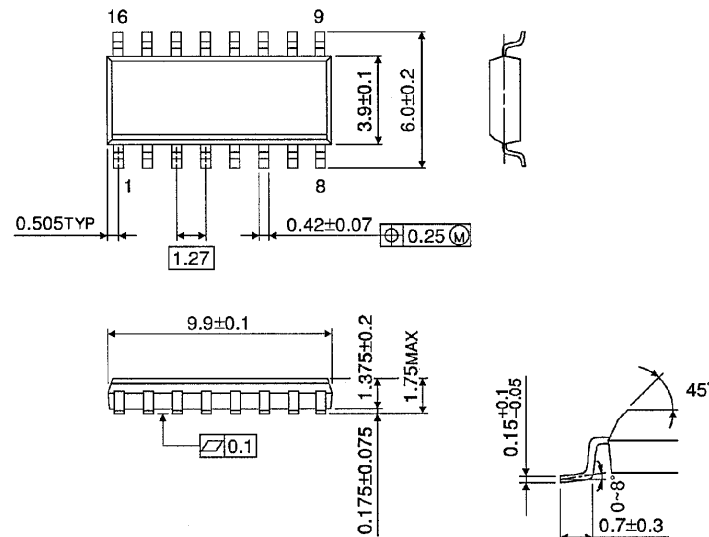
Unit in mm



Weight : 0.18g (Typ.)

Unit in mm

(Note) This package is not available in Japan.



Weight : 0.13g (Typ.)

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